

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

#3

ATTY DOCKET NO.

2002US304

SERIAL NO.

10/042,878

Neisser et al

FILING

01/09/2002

GROUP

1756

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
mb	4,557,797	12/10/1985	Fuller et al	438	514	
	4,863,827	09/05/1989	Jain et al	430	145	
	4,910,127	03/20/1990	Arnold et al	430	313	
	5,635,333	06/03/1997	Peterson et al	430	311	
	5,652,297	07/29/1997	McCulloch et al	524	555	
	5,886,102	03/23/1999	Sinta et al	525	15	
	5,939,236	08/17/1999	Pavelcheck et al	430	271.1	
	5,981,145	11/09/1999	Ding et al	430	271.1	
	6,042,990	03/28/2000	Shao et al	430	271.1	
	6,080,530	06/27/2000	Shao et al	430	325	
mb	6,110,653	08/29/2000	Holmes et al	430	325	

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
mb	GB 2 135 793 A	09/05/1984	UK				
	GB 2 357 509	06/27/2001	UK				
	EP 0 542 008 A1	05/19/1993	Europe				
mb	EP 0 813 114 A2	05/28/1997	Europe				

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

mb	James Fahey et al, "Design of a Bottom Anti-Reflective Layer for Optical Lithography", SPIE, Vol. 2195, pages 422 - 446
----	---

EXAMINER

*Michael R. ...*

DATE CONSIDERED

4/24/03

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

#3

ATTY DOCKET NO.

2002US304

SERIAL NO.

10/042,878

Neisser et al

FILING

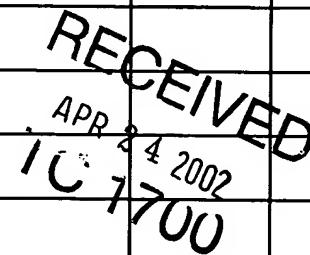
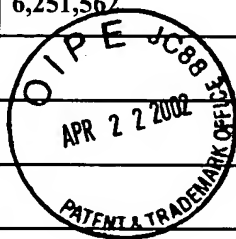
01/09/2002

GROUP

1756

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
W17	6,114,085	09/05/2000	Padmanaban et al	430	270.1	
	6,187,506	02/13/2001	Ding et al	430	271.1	
	6,242,161	06/05/2001	Kawaguchi et al	430	313	
W17	6,251,562	06/26/2001	Breyta et al	430	287.1	



## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

W17		C. Nolscher et al, "High contrast single layer resists and antireflection layers - an alternative to multilayer resist techniques", SPIE, Vol. 1086, 1989, pages 242 - 250

EXAMINER

*Michael G...*

DATE CONSIDERED

6/24/03

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

2002US36

Application Number

10/042,878

Applicant(s)

Mark O. Neisser et al

Filing Date

January 9, 2002

Group Art Unit

1756

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
nm		6,054,254	04/25/2000	Yasuhiko Sato et al	430	322	
nm		6,261,743 B1	07/17/2001	Pavelcheck et al	430	325	
		<del>6,114,085 A</del>	<del>09/05/2000</del>	<del>Padmanaban et al</del>			
		<del>6,110,653 A</del>	<del>08/29/2000</del>	<del>Steven Holmes et al</del>			

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

*Mark O. Neisser*

DATE CONSIDERED

6/24/03

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

JUN 02 2003

Docket Number (Optional)

2002US30

Application Number

10/042,878

Applicant(s)

Mark O. Neisser et al

Filing Date

January 9, 2002

Group Art Unit

1756

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
ny		4,557,996 A	12/10/1985	Toshimi Aoyama et al	430	324	
ny		5,695,910 A	12/09/1997	Fumiyoshi Urano et al	430	270.1	
		<del>5,939,236 A</del>	<del>08/17/1999</del>	<del>Edward K. Pavelcheck et al</del>			
		<del>6,261,743 B1</del>	<del>07/17/2001</del>	<del>Edward K. Pavelchok et al</del>	430	324	
ny		6,319,651 B1	11/20/2001	Steven J. Holmes et al			

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
		<del>EP 0 542 008 A</del>	<del>05/19/1993</del>	<del>Europe</del>				
ny		EP 0 726 500 A	08/14/1996	Europe				
		<del>EP 0 813 114 A</del>	<del>12/17/1997</del>	<del>Europe</del>				

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.